INNOVATE

ELECTRONICS

& MTO Symposium

The Problem

NCH FAB

- Significant barriers exist to commercializing novel micro- and nanoscale devices which leverage semiconductor fabrication technologies
 - Standardized processes largely do not exist for novel devices (e.g. MEMS) _
 - Dedicated fab facilities for R&D and production are prohibitively expensive ____
 - Process development cycles via foundry services can be prohibitively long —

The Solution

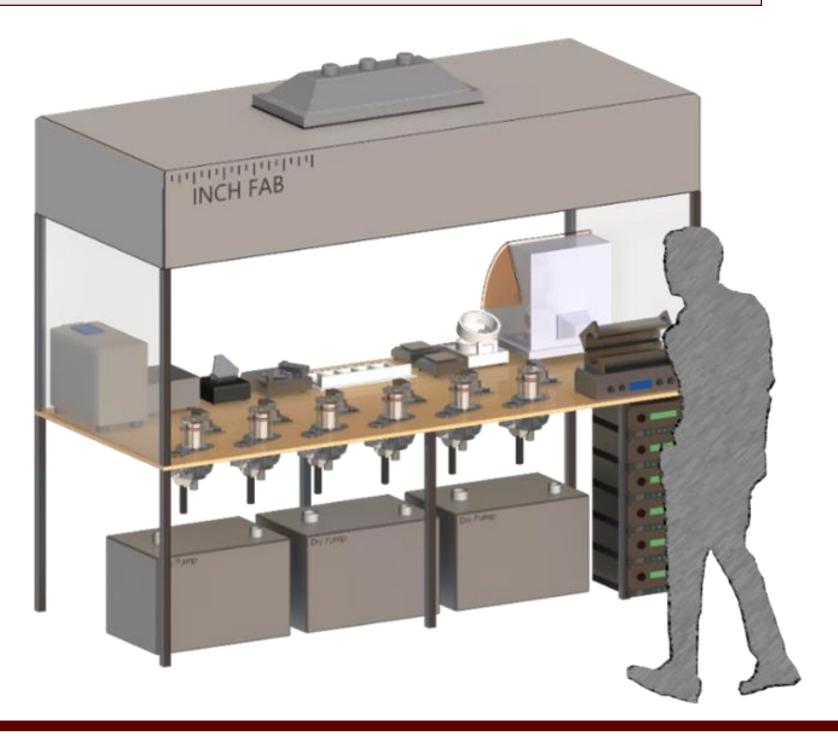
- Inchfab's solution is an integrated toolset that processes 2" substrates and cumulatively costs less than \$1M
 - Incorporates modern processing techniques and performance standards —
 - Provides substantially lower capital and operating costs —
 - Enables local, economical device development and small-scale production —

<u>Approach</u>

• We envision the Inchfab platform having all the tools required to produce MEMS devices initially and eventually advanced deep sub-micron devices

 Deep Reactive Ion Etching (DRIE) 	Reactive le
Plasma Enhanced CVD (PEVCD)	Low Press
 Oxidation / Diffusion / Annealing 	Physical V
 Lithography / Mask Alignment 	• Wet Proce
• Wafer Bonding (Anodic / Fusion)	 Inspection

- Tools are designed to be inexpensive, modular, and easy to use
 - Accelerates development of new tools and processes
 - Offers path to scale up capabilities as resources expand
- A full set of Inchfab tools can be housed in a laminar flow hood for self-contained, cleanroom-grade wafer processing



Mitchell Hsing and Parker Gould, Inchfab Inc. Activate Cyclotron Road Fellows

- Ion Etching (RIE)
- sure CVD (LPCVD)
- Vapor Deposition (PVD)
- essing (Etch / Clean)
- n (SEM / Optical / Probe)

Defense Applications

- High-Mix, Low-Volume
- Legacy Parts
- Die Level Packaging
- Heterogeneous integration

Market Applications

- Rapid R&D and Startups
- Low-medium volume markets MEMS
- Small die size applications
 - Small die size \rightarrow low wafer volumes

PECVD

- High density plasma
- SiO_2 , SiN_x , and a-Si
- Uniformity: <3%
- 25-150°C deposition temperature
- Tunable refractive index, stress, and conformality

<u>SiN_x Stress Tuning</u> 1.6 1.8 2.0 2.2 2.4 N₂ Flow (sccn

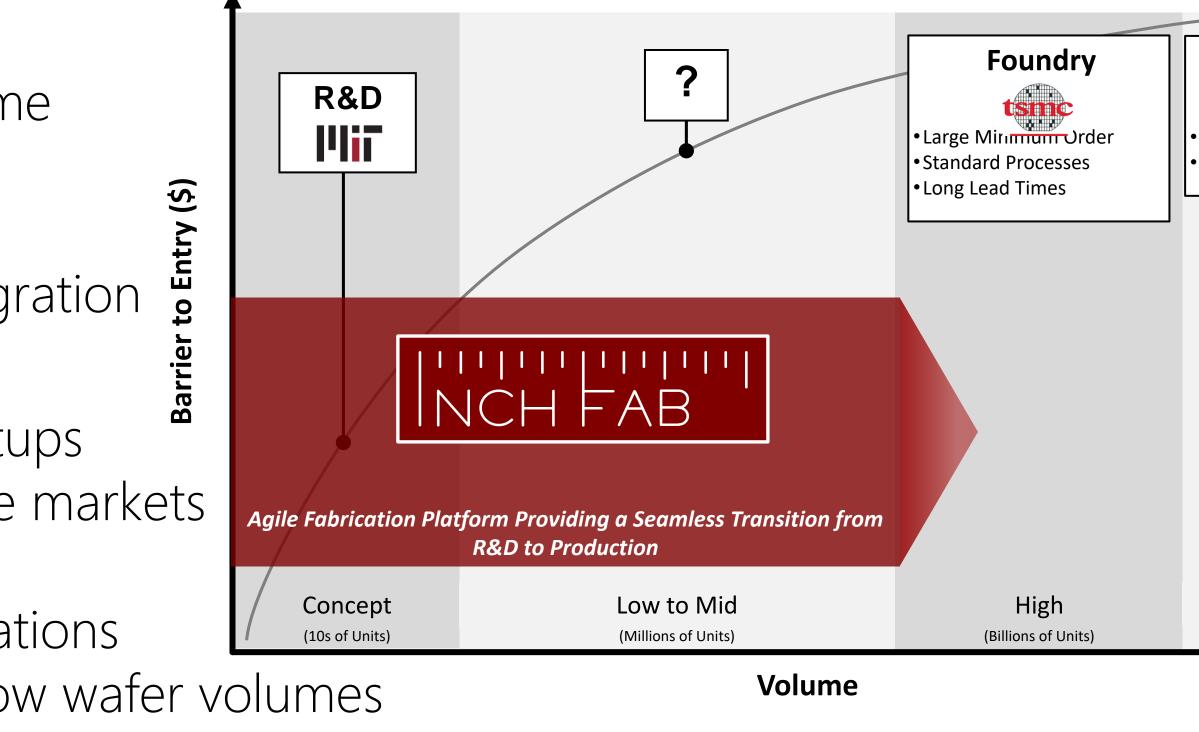
- The Inchfab platform will democratize microfabrication and reenergize domestic fabrication by enabling: • "Internet of Fabs" powered by Recipe App Store • Secure domestic supply chains – Trusted Fabs • Microfabrication makerspaces

This research was developed with funding from the Defense Advanced Research Projects Agency (DARPA). The views, opinions and/or findings expressed are those of the author and should not be interpreted as representing the official views or policies of the Department of Defense or the U.S. Government. Distribution Statement A – Approved for Public Release, Distribution Unlimited.

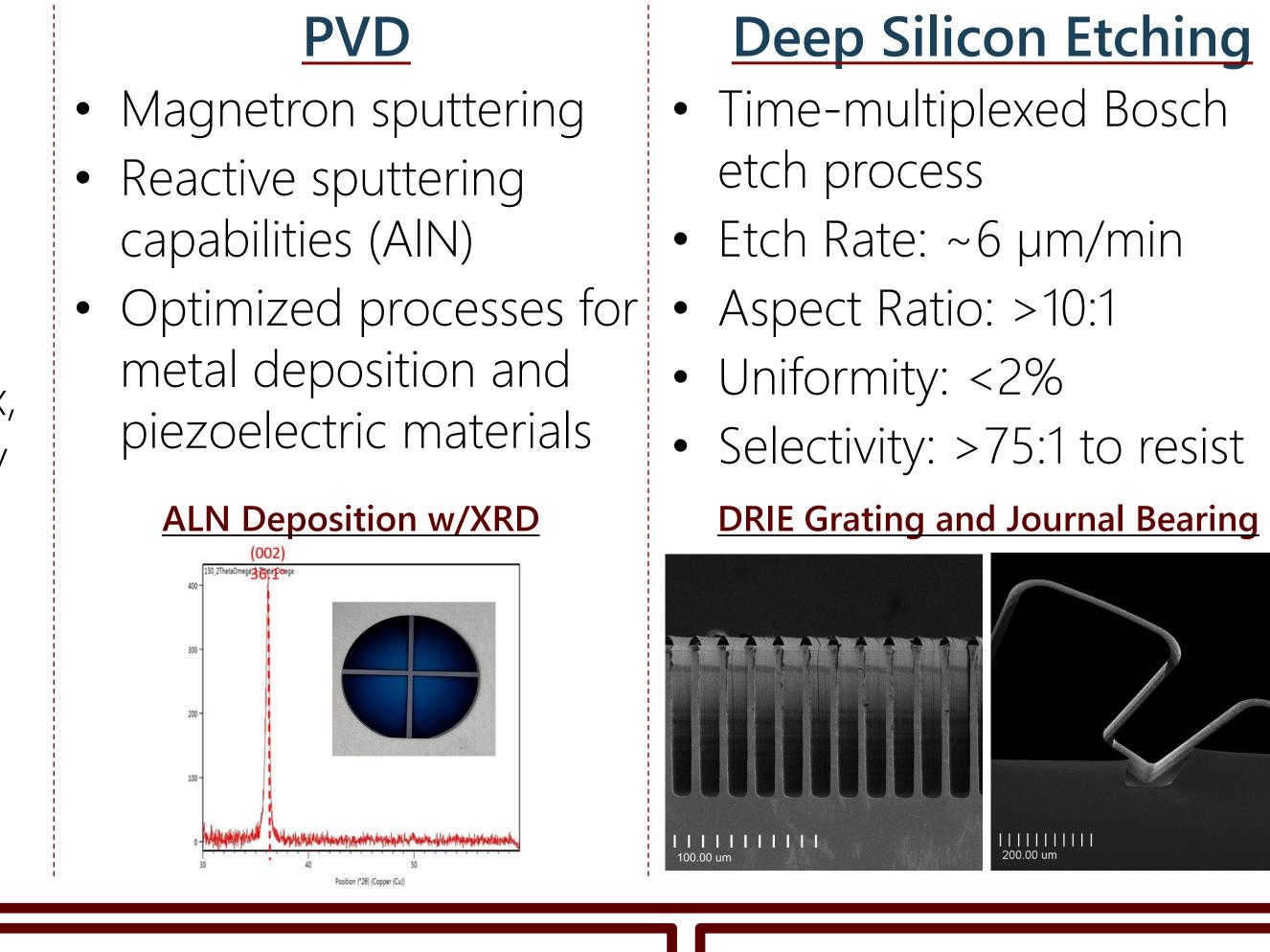


Security and Access

Platform Applications



Selected Results



Impact

Contact Mitchell Hsing | CEO mhsing@inchfab.com Parker Gould | CTO

pgould@inchfab.com

